INFORMATION DISCLOSURE CITATION				Atty Docket: 061450/0304605		Serial No.		
PTO-1449				FID-101-D1		to be assigned		
Applicant: S. Prakash								
Submitted: July 3, 2003				Filing Date: Herewith		Prior Group Art Unit:		
EXAMINER'S					THE PROPERTY.		FILING DATE	
INITIALS	PATENT NO.	DATE	NAME		CLASS	SUBCLASS		
Re	5,723,981	03 Mar 1998	Hellemans et al.		324	719	06/25/96	
Ø_	5,992,226	11/1999	Green et al.		73	105		
RR	5,763,768	06/1998	Henderson, et al.		73	105		
					1			
	·				1			
					1			
						·		
		<u> </u>						
			 					
	TO BUILD THE	AN ENEORE	I IGN PATI	ENT DOCUMENTS	ACT OF A S		TOTAL PARTY	
FYAMINEDIC					HELD SH T	SIADEN II POLIT	Translation	
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY		CLASS	SUBCLASS		
							Yes No	
Line Talance	TOTHER DOCU	MENTS (Incl	uding At	ithor, Title Date, Pertine	nt Rage	s Etc!) Si		
OTHER DOCUMENTS (Including Author Title Date Pertinent Rages Etc.) De Wolf, et al. "Lateral and vertical dopant profiling in semiconductors by atomic force microscopy using								
RR	conducting tops" (J. Vac. Sci. Tech. A 13(3), May/June 1995, pp. 1699-1704							
•								
	<u> </u>			· - · · · · · · · · · · · · · · · · · ·				
	ONEIL		,		2 4	5-04	_	
EXAMINER RAZVIS				DATE CONSIDERED 2 - 3				

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.